N-channel 100V $12m\Omega$ standard level MOSFET in LFPAK

Rev. 04 — 23 February 2010

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel MOSFET in LFPAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

1.4 Quick reference data

Table 1. Quick reference

- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package
- Motor control
- Server power supplies

Table 1.	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	100	V
I _D	drain current	T _{mb} = 25 °C; see <u>Figure 1</u>	-	-	60	А
P _{tot}	total power dissipation	$T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 2}{\text{Figure } 2}$	-	-	130	W
Tj	junction temperature		-55	-	175	°C
Avalancl	he ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy		-	-	170	mJ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; \text{ I}_{D} = 45 \text{ A};$	-	19	-	nC
Q _{G(tot)}	total gate charge	V _{DS} = 50 V; see <u>Figure 14</u> and <u>15</u>	-	64	-	nC



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Table 1. Quick reference continued						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static c	haracteristics					
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	23	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 13</u>	-	10	12	mΩ

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	
3	S	source		
4	G	gate	Q	
mb	D	mounting base; connected to drain		mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Orde	Table 3. Ordering information					
Type number	Package					
	Name	Description	Version			
PSMN012-100Y	S LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669			

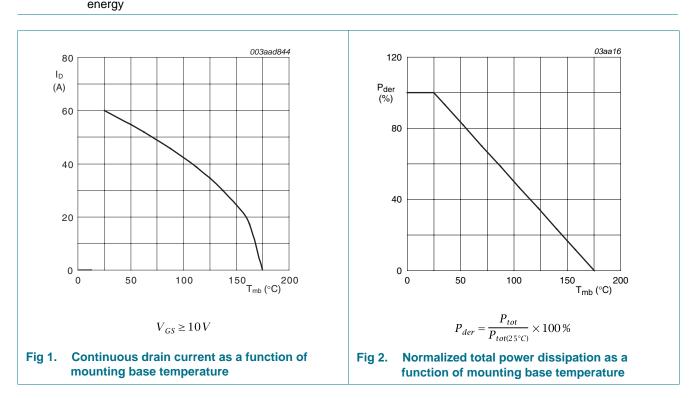
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4. Limiting values

Table 4. Limiting values

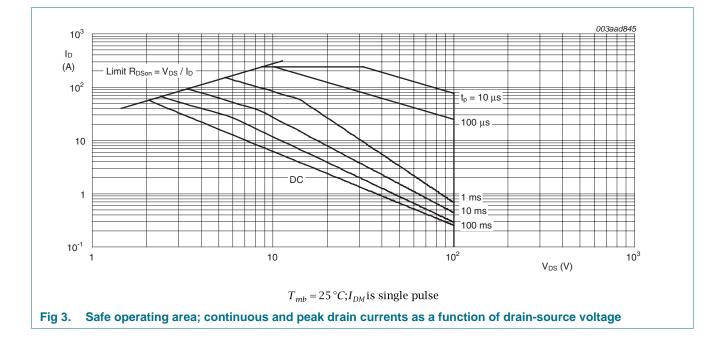
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	100	V
V _{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	100	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	T _{mb} = 100 °C; see <u>Figure 1</u>	-	43	А
		T _{mb} = 25 °C; see <u>Figure 1</u>	-	60	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	242	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	130	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
T _{sld(M)}	peak soldering temperature		-	260	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	60	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	242	А
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 60 A; V_{sup} \leq 100 V; R_{GS} = 50 $\Omega;$ unclamped	-	170	mJ



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PSMN012-100YS



δ

t_p (s)

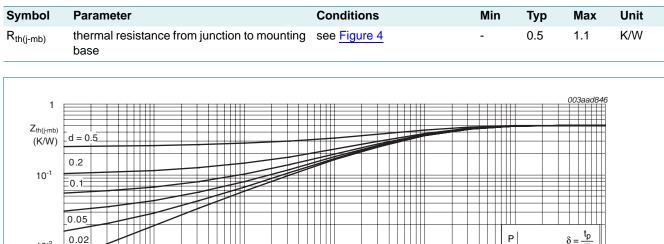
1

tp

10⁻¹

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5. **Thermal characteristics**



10⁻³

Transient thermal impedance from junction to mounting base as a function of pulse duration; typical

10⁻²

Table 5. **Thermal characteristics**

10⁻²

10⁻³ 10⁻⁶

Fig 4.

~ single shot

values

10⁻⁵

10⁻⁴

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6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
•	racteristics					
V _{(BR)DSS}	drain-source	I _D = 0.25 mA; V _{GS} = 0 V; T _i = -55 °C	90	-	-	V
	breakdown voltage	$I_{\rm D} = 0.25 \text{ mA; } V_{\rm GS} = 0 \text{ V; } T_{\rm i} = 25 \text{ °C}$	100	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 10	0.95	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see Figure 11 and 10	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 10</u>	-	-	4.6	V
I _{DSS}	drain leakage current	V_{DS} = 100 V; V_{GS} = 0 V; T_j = 125 °C	-	-	100	μA
		V _{DS} = 100 V; V _{GS} = 0 V; T _j = 25 °C	-	0.06	5	μA
I _{GSS}	gate leakage current	V_{GS} = 20 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
		V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 100 °C; see <u>Figure 12</u>	-	-	23	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 175 °C; see <u>Figure 12</u>	-	27	35.8	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 13</u>	-	10	12	mΩ
R _G	internal gate resistance (AC)	f = 1 MHz	-	0.7	-	Ω
Dynamic o	haracteristics					
Q _{G(tot)}	total gate charge	$I_D = 0 \text{ A}; \text{ V}_{DS} = 0 \text{ V}; \text{ V}_{GS} = 10 \text{ V}$	-	51	-	nC
		$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$	-	64	-	nC
Q _{GS}	gate-source charge	see Figure 14 and 15	-	14.9	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14	-	10.2	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	4.7	-	nC
Q _{GD}	gate-drain charge	$I_D = 45 \text{ A}; V_{DS} = 50 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 14 and 15	-	19	-	nC
V _{GS(pl)}	gate-source plateau voltage	V_{DS} = 50 V; see <u>Figure 14</u> and <u>15</u>	-	4.4	-	V
C _{iss}	input capacitance	V _{DS} = 50 V; V _{GS} = 0 V; f = 1 MHz; T _j = 25 °C;	-	3500	-	pF
C _{oss}	output capacitance	see Figure 16	-	246	-	pF
C _{rss}	reverse transfer capacitance		-	149	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 50 \text{ V}; \text{ R}_{L} = 1.1 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	23	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \ \Omega; \ T_{j} = 25 \ ^{\circ}C$	-	31	-	ns
t _{d(off)}	turn-off delay time		-	52.5	-	ns
t _f	fall time		-	25	-	ns

Symbol

Source-drain diode

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Max

Unit

Тур

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Min

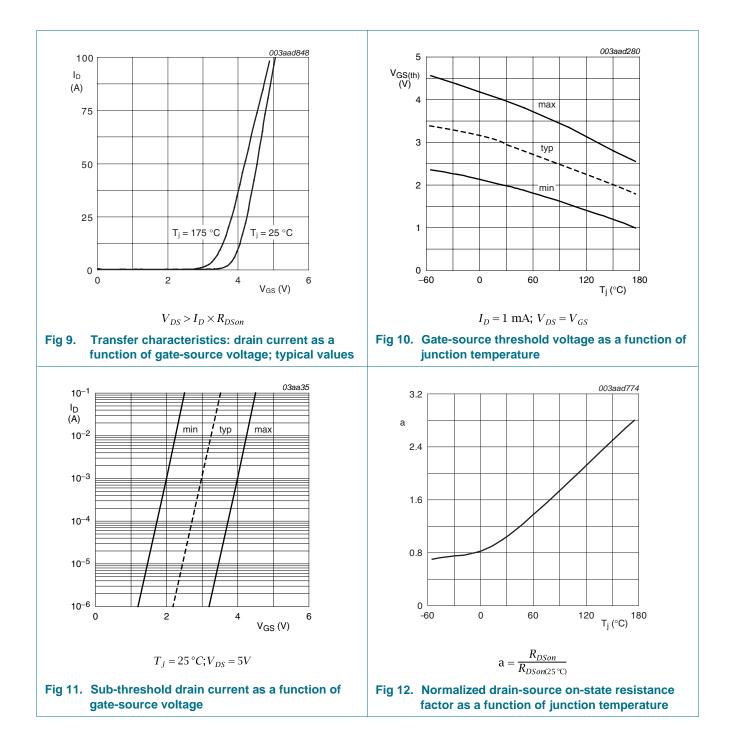
SD	source-drain voltage	$I_{S} = 15 \text{ A}, V_{GS} = 0 \text{ V}, 1$	_j = 25 °C; see <u>Figure 17</u>	-	0.8	1.2	V
	reverse recovery time		A/ μ s; V _{GS} = 0 V;	-	56	-	ns
r	recovered charge	V _{DS} = 50 V		-	129	-	nC
		0001040				000	
12	20	003aad849	6000			003aad850	
g _{fs} (S)			C (pF)				
9	90						
			4000				
-							
6	50					Crss	
			2000				
3	30						
	o /		0				
	0 25 50	75 _{I_D (A)} 100	0 3	6	9	V _{GS} (V) 12	2
	$T \rightarrow C \cdot V$			1 014-6	1 1 477 -		
	$T_j = 25 ^{\circ}C; V_D$	s = 20 V		$V_{DS} = 0 V; f$			
ig 5.	Forward transconduct	$s_s = 20V$ ance as a function of	Fig 6. Input and re	everse tra	nsfer cap		
ig 5.		$s_s = 20V$ ance as a function of alues		everse tra	nsfer cap	e; typica	values
	Forward transconduct	$s_s = 20V$ ance as a function of	Fig 6. Input and re	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R _{DSor}	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap	e; typica	values
R _{DSor} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	l values
R _{DSor} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica	values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0	l values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0 4.8	l values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	nsfer cap ce voltag	e; typica 003aad847 5.5 5.0	values
R _{DSoi} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5	l values
R _{DSoi} (mΩ)	Forward transconduct drain current; typical v	$s_s = 20V$ ance as a function of alues	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8	l values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	S = 20V ance as a function of alues 003aad852 003ai	Fig 6. Input and refunction of g	everse trai gate-sour	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5	l values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v	$s_{S} = 20V$ ance as a function of alues 003aad852 003aad852 14 VGS (V) 20	Fig 6. Input and refunction of g	everse trai gate-source 1	0.0	e; typica 003aad847 5.5 5.0 4.8 4.5 / _{GS} (V) = 4-	l values
R _{DSol} (mΩ)	Forward transconduct drain current; typical v 40 31 22 13 4 2 4 2 3 4 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 2 3 4 4 2 3 3 4 2 3 3 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 4 4 2 3 3 3 4 3 4 3 4 3 4 4 3 4 3 4 4 3 4 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 4 3 3 4 4 4 3 3 4 4 4 3 3 4 4 4 4 3 3 4 4 4 4 3 4 4 4 4 4 4 4 4 4 4	$s_{S} = 20V$ ance as a function of alues 003aad852 003aad852 14 VGS (V) 20	Fig 6. Input and refunction of g	everse trai gate-source 1	0.0 0.0	e; typica 003aad847 5.5 5.0 4.8 4.5 V _{GS} (V) = 4- V _{DS} (V) ²	I value:

Characteristics ... continued Table 6. Parameter

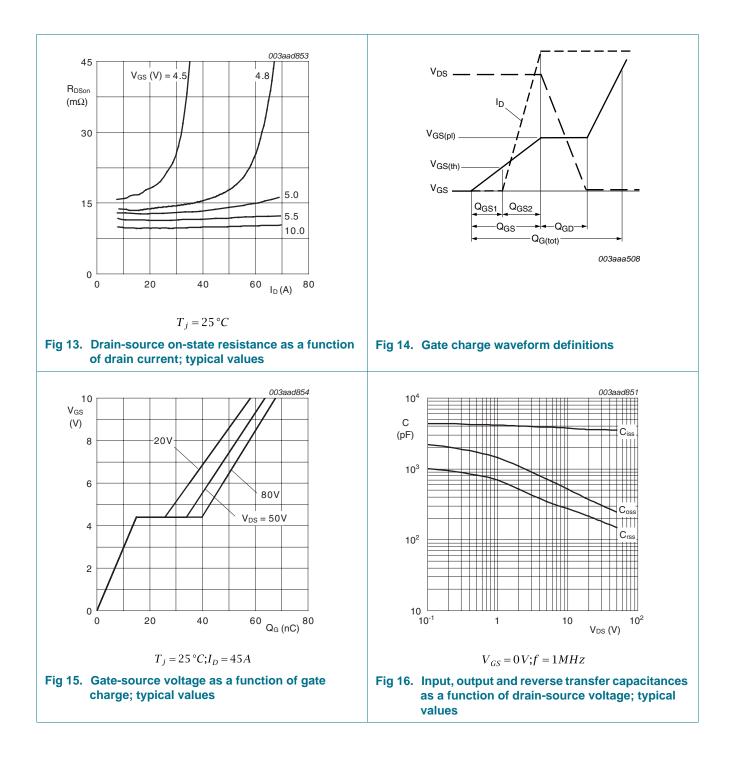
Conditions

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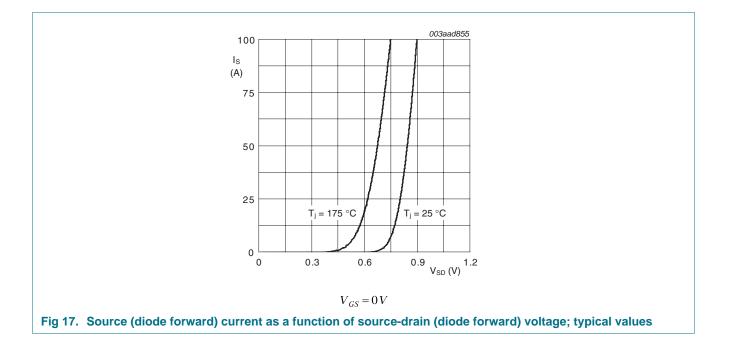
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7. Package outline

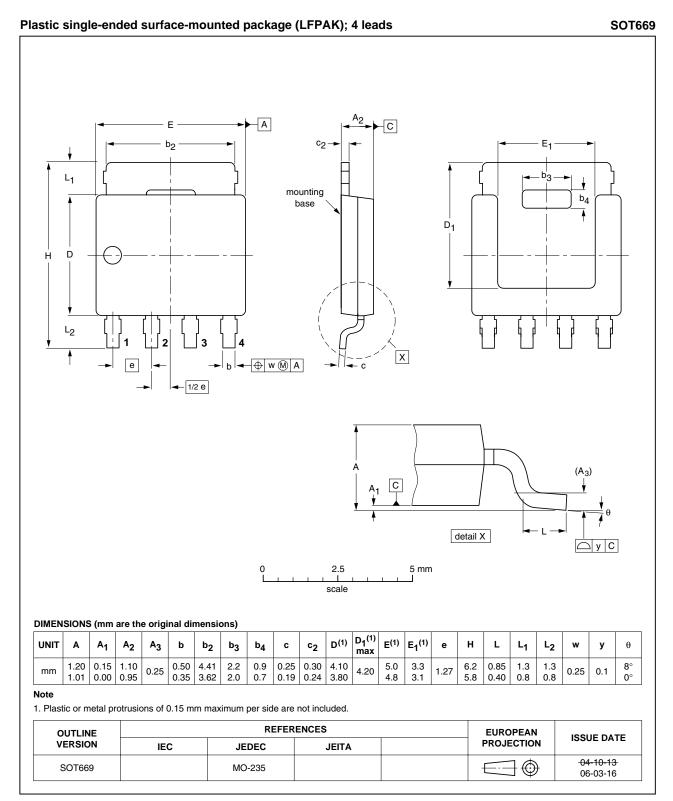


Fig 18. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision his	story			
Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN012-100YS_4	20100223	Product data sheet	-	PSMN012-100YS_3
Modifications:	 Status chai 	nged from objective to pro	oduct.	
PSMN012-100YS_3	20100107	Product data sheet	-	PSMN012-100YS_2
PSMN012-100YS_2	20091214	Objective data sheet	-	PSMN012-100YS_1
PSMN012-100YS_1	20091022	Objective data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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